

### In the Claims

Please SUBSTITUTE the following amended claims for the pending claims with the same number (a marked up copy of the prior pending claim with all changes shown is supplied in the appendix).

Please AMEND the following claims:

24. (Once Amended) An optical inspection system for inspecting the surface of a reticle for defects, comprising:

a light source for emitting an incident light beam along an optical axis;

a first set of optical elements arranged for separating the incident light beam into a plurality of light beams, directing the plurality of light beams to intersect with the surface of the reticle, focusing the plurality of light beams to a plurality of scanning spots on the surface of the reticle, and sweeping the plurality of light beams so as to move the plurality of scanning spots along the surface of the reticle, the plurality of light beams working together to increase the speed of inspection; and

a light detector arrangement including individual light detectors that correspond to individual ones of a plurality of reflected or transmitted light beams caused by the intersection of the plurality of light beams with the surface of the reticle, the light detectors being arranged for sensing the light intensity of either the reflected or transmitted light.

Please ADD claim 47.

47. (New) An optical inspection system for inspecting the surface of a substrate, comprising:

a light source for emitting an incident light beam along an optical axis;

a first set of optical elements arranged for separating the incident light beam into a plurality of light beams, directing the plurality of light beams to intersect with the surface of the substrate, focusing the plurality of light beams to a plurality of scanning spots on the surface of the substrate, the first set of optical elements including a variable magnification subsystem disposed along the optical axis, the variable magnification subsystem being arranged for controlling the scanning spot size; and